

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/659,101	CHAN ET AL.	
Examiner	Art Unit	
Randall Chin	1744	

SEARCHED					
Class	Subclass	Oate	Examiner		
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15	167.1	8/1/2005	RC		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor name search	8/1/2005	RC		
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